

Publikationen

- (2021): Scanning Thermal Microscopy of Ultrathin Films: Numerical Studies Regarding Cantilever Displacement, Thermal Contact Areas, Heat Fluxes, and Heat Distribution. In: Nanomaterials, vol. 11, no. 2. DOI: 10.3390/nano11020491.
- (2020): Thermal conductivity measurements of thin films using 3 ω method. In: 7. Tag der Forschung, Deggendorf.
- (2020): Thermal characterization of thin films using FEM simulations. In: 7. Tag der Forschung, Deggendorf.
- (2020): On the Limits of Scanning Thermal Microscopy of Ultrathin Films. In: Materials, vol. 13, no. 3. DOI: 10.3390/ma13030518.
- (2019): Thermische Charakterisierung ultradünner Schichten. In: Forschungsbericht 2018/2019 der Technischen Hochschule Deggendorf, Deggendorf.
- (2019): Temperature dependent investigation of hexagonal boron nitride films using scanning thermal microscopy. Poster presentation. In: 6th Nano Today Conference 2019, Lisbon, Portugal.
- (2018): Investigation of Soft Polymer Surfaces using Atomic Force Microscopy and Laser Scanning Microscopy. In: Applied Research Conference (ARC) 2018, Deggendorf.
- (2018): Investigation of Soft Polymer Surfaces using Atomic Force Microscopy and Laser Scanning Microscopy. In: Applied Research Conference 2018.
- (2018): Investigation of Local Thermal Properties of Carbon Fiber / Epoxy Composites by using Scanning Thermal Microscopy. In: Applied Research Conference (ARC) 2018, Deggendorf.
- (2018): Investigation of Local Thermal Properties of Carbon Fiber / Epoxy Composites by using Scanning Thermal Microscopy. In: Applied Research Conference 2018.
- (2018): Evaluation of Topography effects of SThM Measurements on Thin Thermoelectric Films. Poster. In: 4th Ed. Smart Materials and Surfaces - SMS Conference 2018, Venedig, Italien.
- (2018): Advances in Electrical and Thermal Characterization of Surfaces and Thin Films. Invited Talk. In: 4th Ed. Smart Materials and Surfaces - SMS Conference 2018, Venedig, Italien.
- : Recent Trends in Characterization of Nanoelectronic Materials and Devices with Scanning Probe Microscopy. Invited Talk. In: NanoScientific Symposium China - Scanning Probe Microscopy (SPM), Virtual Conference.